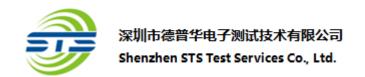


Conduction Immunity Test Result

Applicant :	APTCHIP MICROELECTRONICS CO., LTD							
Location:	The company is located in Shenzhen Nanshan District high tech Industrial Park (South) a high-tech South Wonderland North Block Building Room 301.							
EUT :	APT32F101 TOUCH KEY DEMO BOARD		Model	del Name : APT		T32F101		
Temperature :	21.8℃		Relativ	e Humidity:	52%	2%		
Pressure :	100KPa		Test Da	ate :	2017	2017.07.27		
Test Mode :	WORKING		Test Po	ower	AC2	AC240V/50HZ		
Test standard	☐ IEC 61000-4-6 ☐ EN 61000-4-6 ☐ other:							
Test Equipment: (1) Conduction Immunity GENERATOR / M/N: CDG-6000-25 126A1280/2014								
(2) 6dB Attenuator ATT-6DB-100 A100W224								
(3) CDN CDN-M2+3 A2210275/2014								
Performance Criterion:	A: Normal performance within limits specified by the manufacturer, request or purchaser							
	B: Temporary loss of function or degradation of performance which ceases after the							
	disturbance ceases, and from which the equipment under test recovers its							
	normal performance, without operator intervention							
	C: Temporary loss of function or degradation of performance, the correction of							
	which requires operator intervention							
	D: Loss of function or degradation of performance which is not recoverable, owing							
	to damage to hardware or software, or loss of data							
Frequency Step:	1_%			⊠ AM 1KHz 80)%	Performance		
Dwell Time:	<u>3000</u> ms	Modulated \$	Signai:	□None		Criterion	Result	
Test Port	Frequency R	ange(MHz)	Applied	Applied Voltage (Vr.m.s.)				
AC Mains	0.15-80			10			PASS	
D.C. Power Lines						A		
Control Line								
Signal Line								
Note: 试验中试验后 EUT 无异常。								



Test Engineer: